


<b>Search Notes</b>  	<b>Application/Control No.</b>  10663516	<b>Applicant(s)/Patent Under Reexamination</b>  CRINON ET AL.
	<b>Examiner</b>  JUNIOR O MENDOZA	<b>Art Unit</b>  4115

SEARCHED			
Class	Subclass	Date	Examiner
725	37, 109, 136	12/20/2007	JM
709	219	12/20/2007	JM

SEARCH NOTES		
Search Notes	Date	Examiner
Spoke to Ryan Yang	12/20/2007	JM
EAST search	12/20/2007	JM
<a href="http://en.wikipedia.org/wiki/Main_Page">http://en.wikipedia.org/wiki/Main_Page</a>	12/20/2007	JM
<a href="http://www.ipdl.inpit.go.jp/homepg_e.ipdl">http://www.ipdl.inpit.go.jp/homepg_e.ipdl</a>	12/20/2007	JM

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner